

<b>Search Notes</b>  <b>*1066071</b>  <b>0*</b>	<b>Application/Control No.</b>  10660710	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANO ET AL.
	<b>Examiner</b>  LUONG T NGUYEN	<b>Art Unit</b>  2622

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
348/294, 312, 317, 322, 262, 263 (text search)	11/07/09	LTN
EAST (USPAT; USPGPUB; JPO; EPO; DERWENT; IBM_TDB) see search history	11/07/09	LTN
348/272 (text search)	07/01/10	LTN
EAST (USPAT; USPGPUB; JPO; EPO; DERWENT; IBM_TDB) see search history	07/01/10	LTN
updated East	02/27/11	LTN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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